

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re PATENT APPLICATION of

Kyoung-Yoon Baek et al.

Group Art Unit: 2814

Serial No.: 10/043,329

Examiner: Rao, Shrinivas H.

Filed: 14 January 2002

For: OVERLAY KEY, METHOD OF MANUFACTURING THE SAME AND METHOD OF MEASURING AN OVERLAY DEGREE USING THE SAME C 2800 MAIL ROOM

RECEIVED

RESPONSE TO ELECTION/RESTRICTION REQUIREMENT

U.S. Patent and Trademark Office 2011 South Clark Place Customer Window, **Mail Stop Non-Fee Amendment** Crystal Plaza Two, Lobby, Room 1B03 Arlington, VA 22202

Sir:

In response to the Office Action of 29 September 2003, Applicants elect the invention of Group I, Claims 1-24, drawn to an overlay key. The election is without traverse.

Respectfully submitted,

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